



THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicants: KOMURA et al.

Serial No.: 09/616,372

Filed: 7/13/2000

Title: METHOD FOR MEASURING
THICKNESS OF OXIDE FILM

Atty. Dkt.: 01-50

Art Unit: 2881

Examiner: Souw

Mail Stop AF

Commissioner for Patents
U.S. Patent and Trademark Office
2011 South Clark Place
Crystal Plaza Two, Lobby, Room 1B03
Arlington, VA 22202

Date: 26 March 2004

AMENDMENT UNDER 37 CFR 1.116

Sir:

In response to the office action mailed 5 December 2003, please amend the application as follows:

Amendments to the Specification begin on page 2 of this paper.

Amendments to the Claims are reflected in the listing of claims that begins on page 4 of this paper.

Remarks begin on page 10 of this paper.